

Enhanced Correlation Coefficient Maximization: Mathematical Theory

1 Enhanced Correlation Coefficient (ECC)

The Enhanced Correlation Coefficient (ECC) is used to measure the alignment between two image profiles: a reference image $I_r(x)$ and a distorted image $I_w(y)$. The ECC criterion is defined as:

$$EECC(p) = \left\| \frac{\bar{\mathbf{I}}_r}{\|\bar{\mathbf{I}}_r\|} - \frac{\bar{\mathbf{I}}_w(p)}{\|\bar{\mathbf{I}}_w(p)\|} \right\|^2, \quad (1)$$

where:

- $\bar{\mathbf{I}}_r$: Zero-mean version of the intensity vector for the reference image.
- $\bar{\mathbf{I}}_w(p)$: Zero-mean version of the intensity vector for the warped image with parameter p .
- p : Vector of parameters controlling the geometric transformation.

The objective is to maximize the correlation defined as:

$$\phi(p) = \frac{\bar{\mathbf{I}}_r^\top \bar{\mathbf{I}}_w(p)}{\|\bar{\mathbf{I}}_r\| \|\bar{\mathbf{I}}_w(p)\|}. \quad (2)$$

This function is invariant to photometric distortions such as changes in contrast and brightness.

2 Geometric Transformation

The transformation of coordinates is modeled parametrically:

$$y = \psi(x; p), \quad (3)$$

where:

- $x = [x_1, x_2]^\top$: Coordinates in the reference image.
- $y = [y_1, y_2]^\top$: Coordinates in the warped image.
- $\psi(x; p)$: Parametric transformation function (e.g., affine, homography).

3 Optimization Formulation

The alignment problem can be formulated as:

$$\min_p E(p) = \min_p \|\mathbf{I}_r - \mathbf{I}_w(\psi(x; p))\|^2. \quad (4)$$

To account for intensity changes, a photometric model can be included:

$$\min_{p, \theta} E(p, \theta) = \min_{p, \theta} \sum_{x \in T} |I_r(x) - \gamma \cdot I_w(\psi(x; p)) - \beta|^2, \quad (5)$$

where γ and β are parameters for contrast and bias.

In ECC, we focus only on geometric components by normalizing the intensity vectors to have zero mean.

4 Linear Approximation

The nonlinear transformation $I_w(\psi(x; p))$ is approximated using a first-order Taylor expansion:

$$I_w(\psi(x; p)) \approx I_w(\psi(x; \tilde{p})) + J(\tilde{p})\Delta p, \quad (6)$$

where:

- $J(\tilde{p})$: Jacobian matrix computed at the current parameter \tilde{p} .
- $\Delta p = p - \tilde{p}$: Parameter update vector.

Thus, the intensity vector for the warped image becomes:

$$\mathbf{I}_w(p) \approx \mathbf{I}_w(\tilde{p}) + G(\tilde{p})\Delta p, \quad (7)$$

where $G(\tilde{p})$ is the Jacobian that maps parameter changes to intensity changes.

5 Iterative Algorithms

5.1 Forward Additive ECC

This method iteratively updates the parameters:

$$p_j = p_{j-1} + \Delta p, \quad (8)$$

where Δp is obtained by maximizing the approximated objective function:

$$\phi(\Delta p | \tilde{p}) = \frac{\bar{\mathbf{I}}_r^\top (\bar{\mathbf{I}}_w + G\Delta p)}{\|\bar{\mathbf{I}}_r\| \|\bar{\mathbf{I}}_w + G\Delta p\|}. \quad (9)$$

5.2 Inverse Compositional ECC

In this efficient variant, the roles of the reference and warped images are interchanged. The Jacobian is computed once for the reference image:

$$p \leftarrow \psi^{-1}(x; p). \quad (10)$$

This reduces the computational complexity significantly.

6 Relation to SSD-Based Methods

ECC is compared to Sum of Squared Differences (SSD) methods like Lucas-Kanade:

- ECC optimizes normalized correlation, making it robust to photometric distortions.
- SSD minimizes intensity differences, which are sensitive to brightness changes.

7 Performance Evaluation

7.1 Error Metric

The squared error for iteration j is defined as:

$$e(j) = \frac{1}{6} \sum_{i=1}^3 \|\psi(x_i; p_r) - \psi(x_i; p_j)\|^2. \quad (11)$$

The Mean Squared Distance (MSD) is computed as the average error over multiple experiments.

7.2 Simulation Results

Simulation experiments show that ECC has:

- Faster convergence.
- Greater robustness to noise and photometric distortions.
- Lower computational complexity in the inverse compositional variant.

8 Conclusion

The ECC method provides an efficient and robust solution for image alignment by maximizing the enhanced correlation coefficient. It outperforms traditional SSD-based methods like Lucas-Kanade, especially under challenging conditions such as noise and photometric distortions.